

## FDPF51N25

28A, 250V N-Channel MOSFET

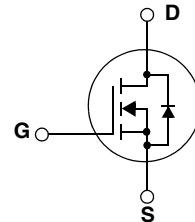
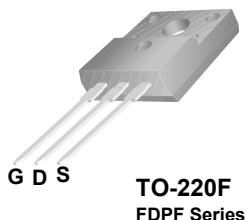
### Features

- $R_{DS(on)} = 0.060 \Omega$  @  $V_{GS} = 10$  V
- Low gate charge ( typical 55 nC)
- Low  $C_{rss}$  ( typical 63 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

### Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



### Absolute Maximum Ratings

Symbol	Parameter	FDPF51N25	Unit
$V_{DSS}$	Drain-Source Voltage	250	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	28 16.8	A A
$I_{DM}$	Drain Current - Pulsed	(Note 1) 112	A
$V_{GSS}$	Gate-Source voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2) 1111	mJ
$I_{AR}$	Avalanche Current	(Note 1) 28	A
$E_{AR}$	Repetitive Avalanche Energy	(Note 1) 11.7	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3) 4.5	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	117 0.93	W W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	1.07	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C}/\text{W}$

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDPF51N25	FDPF51N25	TO-220F	-	-	50

## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

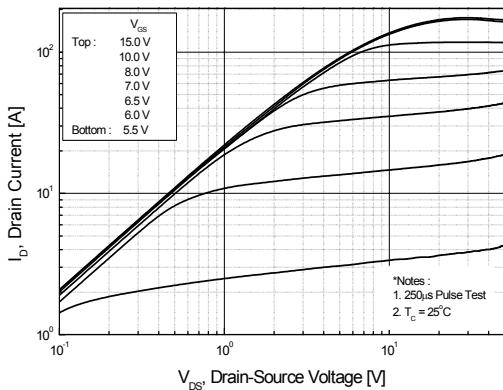
Symbol	Parameter	Conditions	Min.	Typ.	Max	Units
<b>Off Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$	250	--	--	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.25	--	$\text{V}/^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 250\text{V}$ , $V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 200\text{V}$ , $T_C = 125^\circ\text{C}$	-- --	-- 10	1 10	$\mu\text{A}$ $\mu\text{A}$
$I_{\text{GSSF}}$	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	100	nA
$I_{\text{GSSR}}$	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$	3.0	--	5.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10\text{V}$ , $I_D = 14\text{A}$	--	0.048	0.060	$\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{\text{DS}} = 40\text{V}$ , $I_D = 14\text{A}$	(Note 4)	--	43	--
<b>Dynamic Characteristics</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}} = 25\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $f = 1.0\text{MHz}$	--	2620	3410	pF
$C_{\text{oss}}$	Output Capacitance		--	530	690	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		--	63	90	pF
<b>Switching Characteristics</b>						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 125\text{V}$ , $I_D = 51\text{A}$ $R_G = 25\Omega$	--	62	135	ns
$t_r$	Turn-On Rise Time		--	465	940	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	98	205	ns
$t_f$	Turn-Off Fall Time		--	130	270	ns
$Q_g$	Total Gate Charge	$V_{\text{DS}} = 200\text{V}$ , $I_D = 51\text{A}$ $V_{\text{GS}} = 10\text{V}$	--	55	70	nC
$Q_{\text{gs}}$	Gate-Source Charge		--	16	--	nC
$Q_{\text{gd}}$	Gate-Drain Charge		--	27	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	51	A	
$I_{\text{SM}}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	204	A	
$V_{\text{SD}}$	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0\text{V}$ , $I_S = 28\text{A}$	--	--	1.4	V
$t_{\text{rr}}$	Reverse Recovery Time	$V_{\text{GS}} = 0\text{V}$ , $I_S = 51\text{A}$ $dI/dt = 100\text{A}/\mu\text{s}$	--	178	--	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		--	4.0	--	$\mu\text{C}$

### NOTES:

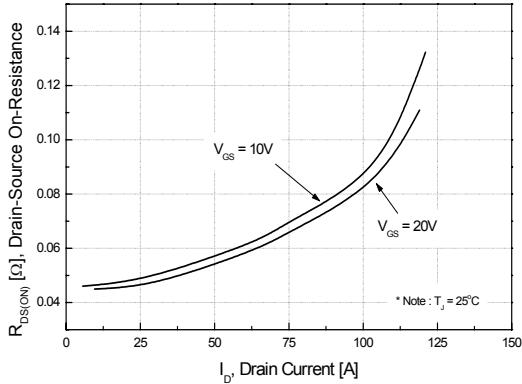
- Repetitive Rating: Pulse width limited by maximum junction temperature
- $L = 2.27\text{mH}$ ,  $I_{AS} = 28\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
- $I_{SD} \leq 28\text{A}$ ,  $dI/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq \text{BV}_{\text{DSS}}$ , Starting  $T_J = 25^\circ\text{C}$
- Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
- Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

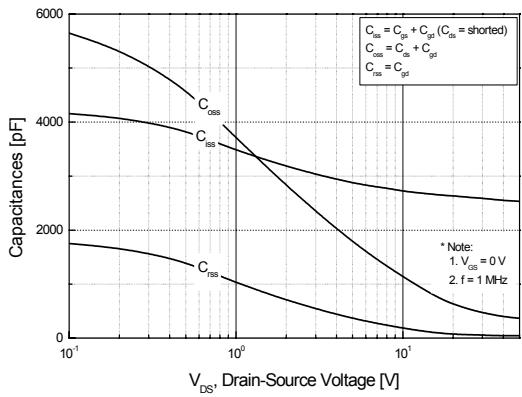
**Figure 1. On-Region Characteristics**



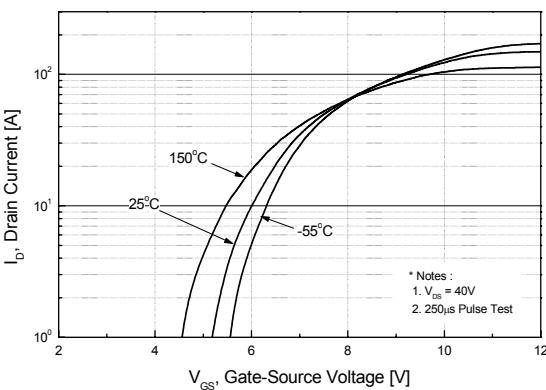
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



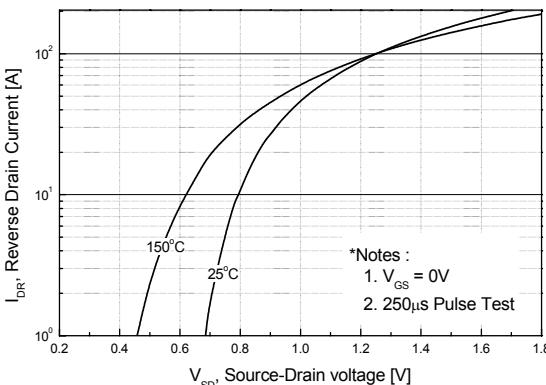
**Figure 5. Capacitance Characteristics**



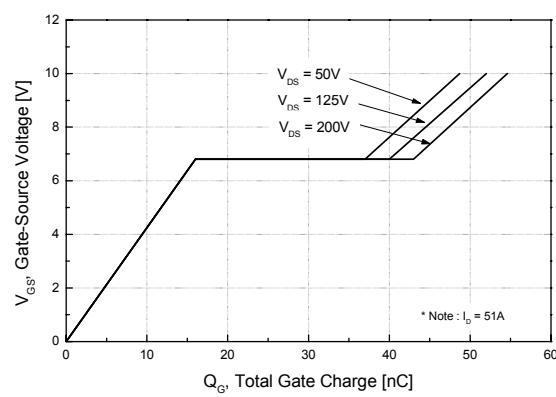
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

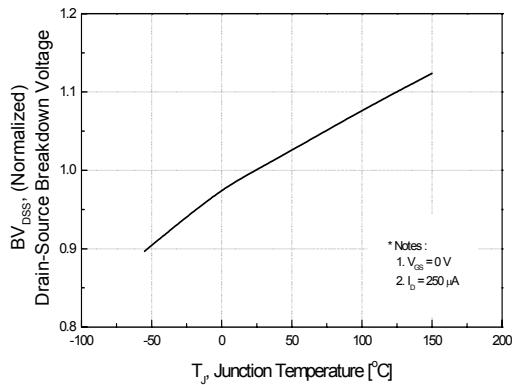


**Figure 6. Gate Charge Characteristics**

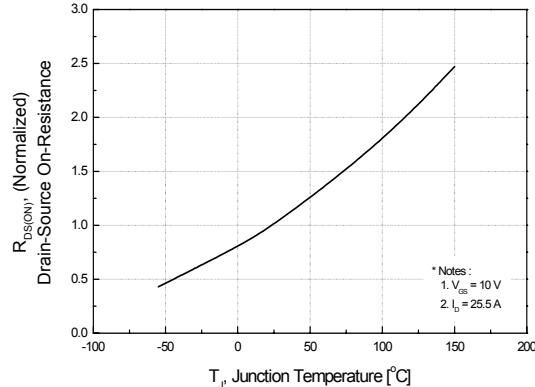


## Typical Performance Characteristics (Continued)

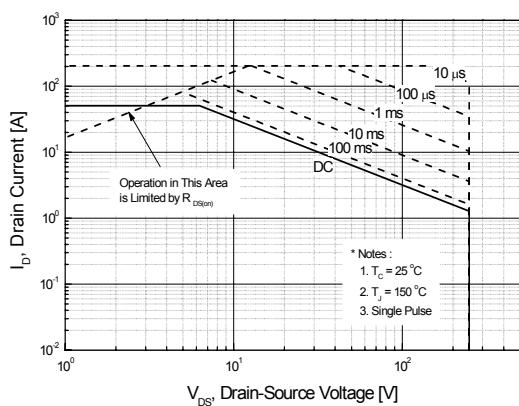
**Figure 7. Breakdown Voltage Variation**



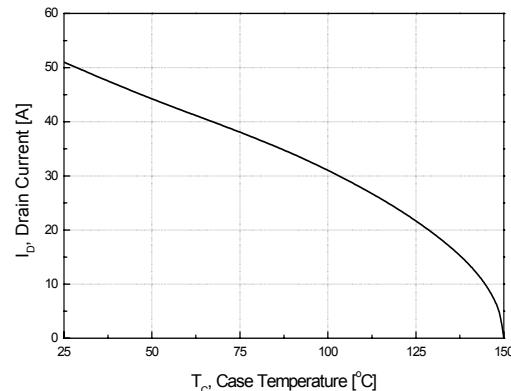
**Figure 8. On-Resistance Variation vs. Temperature vs. Temperature**



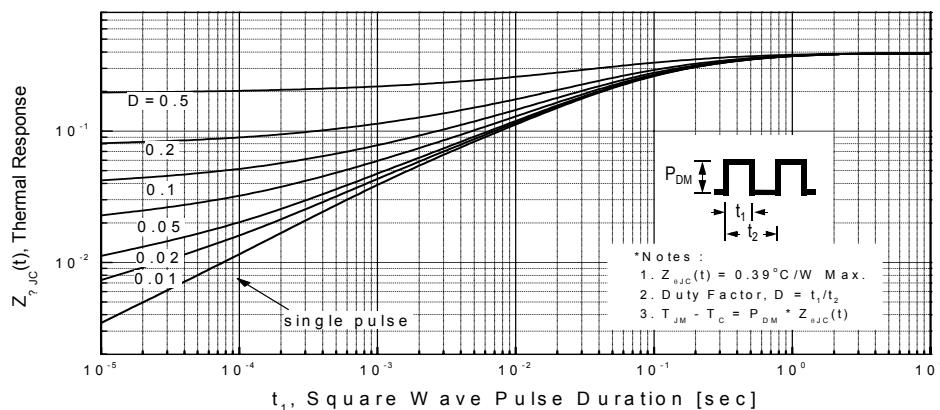
**Figure 9. Maximum Safe Operating Area**



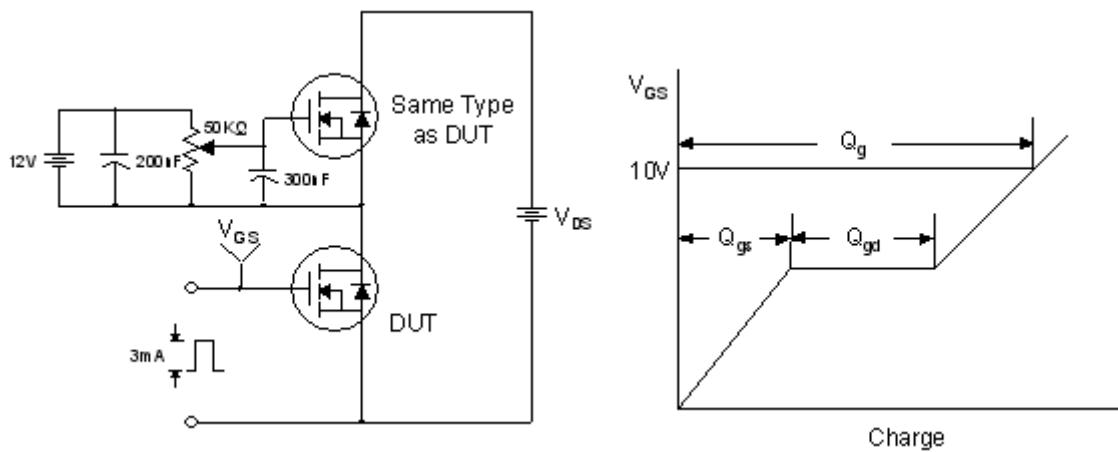
**Figure 10. Maximum Drain Current vs. Case Temperature**



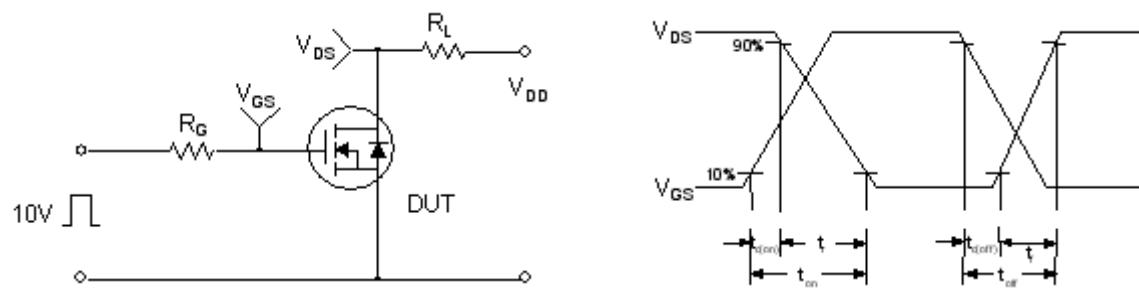
**Figure 11. Transient Thermal Response Curve**



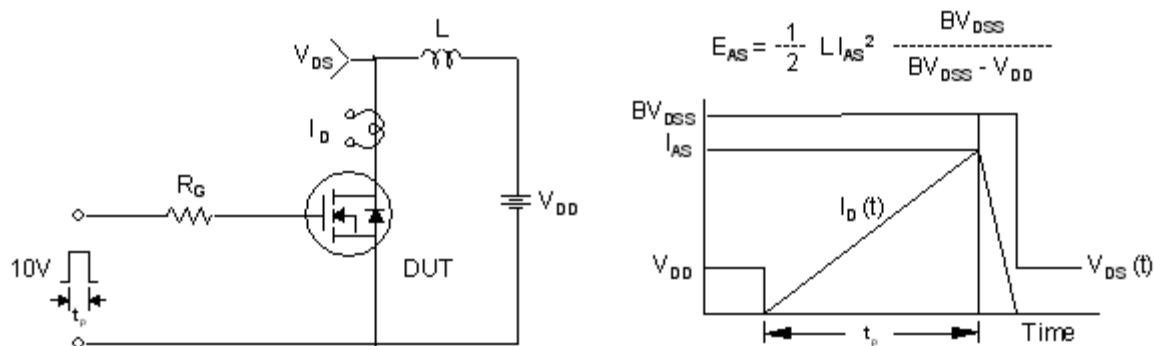
Gate Charge Test Circuit & Waveform



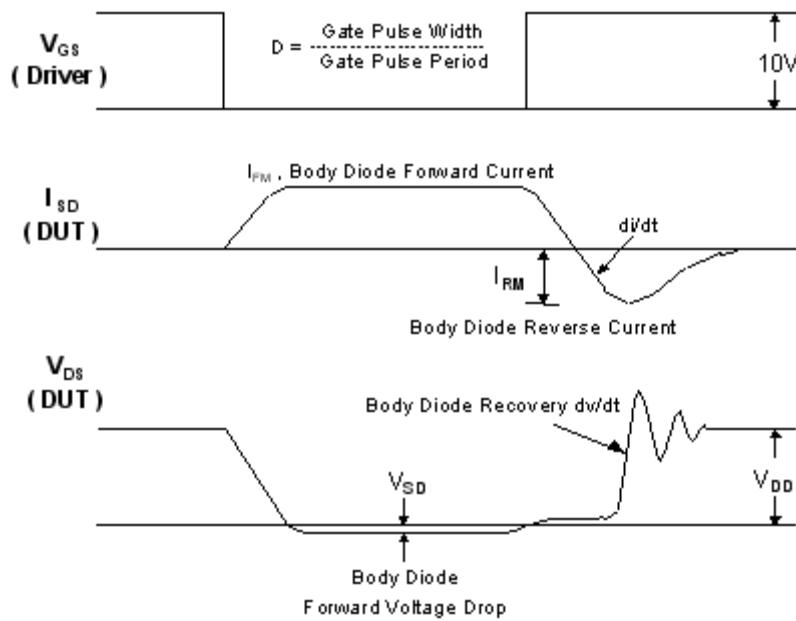
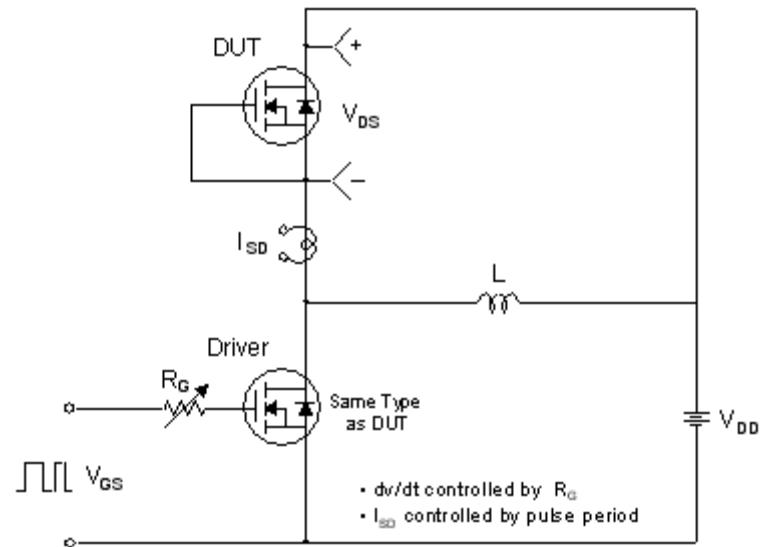
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

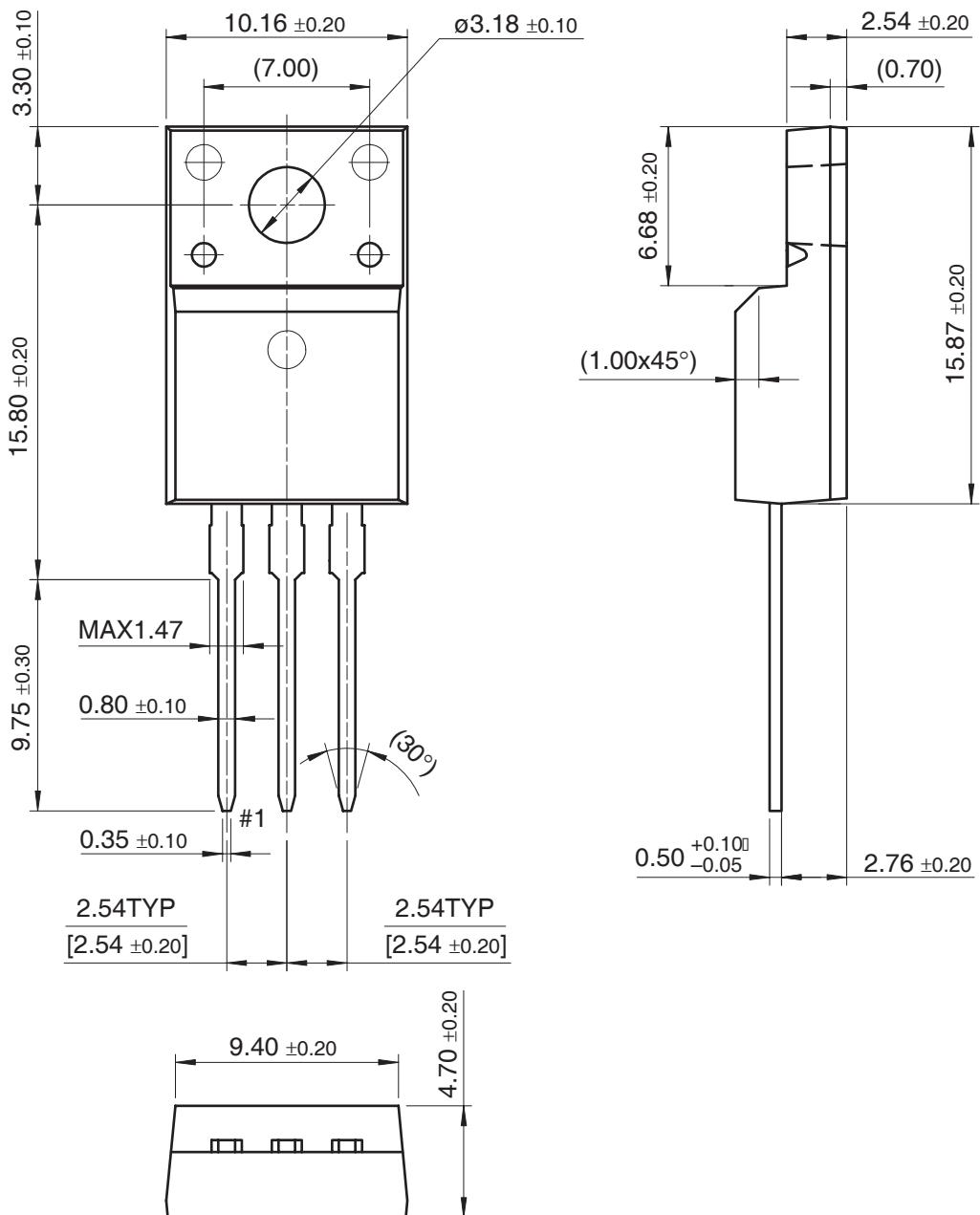


**Peak Diode Recovery dv/dt Test Circuit & Waveforms**



## Mechanical Dimensions

TO-220F



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